

**Search Notes**

Application/Control No.

10/606,243

Examiner

Leon J. Harper

Applicant(s)/Patent under  
Reexamination

HASEGAWA ET AL.

Art Unit

2166

**SEARCHED**

Class	Subclass	Date	Examiner
707	104.1,100, 10,3	10/22/2005	LJH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR